### **The Optical Thomson Scattering Diagnostic**

National ICF Diagnostic Working Group Meeting

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#### LLNL-PRES-XXXXXX

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### A phased approach to Optical Thomson Scattering (OTS) will mitigate the risk presented by background levels

- Phase I
  - Assess background levels around potential probe wavelengths
    - Design and field an optical collection system
      - Supporting Electron Feature not to preclude Ion Feature
    - Alignment to 250 microns for different target types
    - Utilize existing NIF beams for the probe on "simple" experiments (Quartraums, Collisionless Shocks, etc.)
- Phase II
  - Using the background measurements from Phase I validate the probe beam requirements
  - Design and field a Thomson scattering system with a dedicated probe beam to allow measurements on all platforms

Based on the recommendations of the two diagnostic workshops we have developed a phased approach.





### **OTS DIM based diagnostic assembly**

 Optical Thomson Diagnostic is a DIM based diagnostic platform designed to operate in the polar and equatorial locations. Simultaneously records both the electron plasma wave (EPW) and the ion acoustical wave (IAW).



OTS diagnostic DIM platform, telescope, spectrometers, optical streak camera





## OTS optical layout diagram describing optical components of the DIM collection system







### OTS airbox assembly is the first of three key modules in the detector assembly



#### The airbox is assembled off line prior to installation in the final assembly





# OTS airbox configuration describing the complete streak camera assembly



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- Optical streak camera configuration
  - 21 mm spatial region for IAW & EWP spectrum
  - Resolution element ~100 um/pixel
  - FIDU and Comb imprinted on data image
  - Gated cathode operation
  - 4 selectable sweep speeds (5,10,15,35) ns
  - CaF<sub>2</sub> cathode window
    - N<sub>2</sub> beam path from window to optical path



## Clear aperture for streak tube window relative to the comb and FIDU injection







## OTS spectrometer assembly is the second of three modules in the detector assembly



The spectrometer is assembled as an individual module, and characterized prior to assembly into the final DIM assembly.





#### **OTS spectrometer group summary**



#### Spectrometer group features

- EPW & IAW spectrometers (Czerny-Turner type), adjustable gratings
- 135 um entrance hole (shared by both spectrometers)
- Two diodes (entrance and exit) for transmission reference
- Automated IRIS for each leg (filters)
- $\lambda_0$  line masking for IAW
- Alignment camera at pin hole
- ATLAS alignment SMRs



#### **OTS spectrometer group summary**



- Spectrometer Operational Specifications
  - Spectrometers
    - IAW: 206-214 (nm)
    - EPW: 150-200 (nm)
- Measurement Bandwidth:
  - IAW- 4 nm, EPW- 50 nm
- Resolution (δλ/λ):
  - IAW-0.0001, EPW-0.01
- Time resolution: 200 ps
- Time delay between IAW and EPW: 4.9



## Spectrometer ray trace diagram for the EPW and IAW optical paths to photocathode

#### From Telescope



| Spectrometer | Ray Color | Wavelength |
|--------------|-----------|------------|
| EPW          | Blue      | 150nm      |
| EPW          | Green     | 175nm      |
| EPW          | Red       | 200nm      |
| IAW          | Teal      | 208nm      |
| IAW          | Yellow    | 210mn      |
| IAW          | Pink      | 212nm      |





## IAW performance – point spread function at the photocathode

- IAW (~0.6 meter), 2400 l/mm (2<sup>nd</sup> order)
- Point source at center of pinhole, two wavelengths 210nm and 210.021 nm
- Reciprocal linear dispersion at photocathode = 0.2293nm/mm









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### EPW performance – point spread function at the photocathode

- EPW (~0.14 meter), 1200 l/mm (1<sup>st</sup> order)
- Point source at pinhole with two wavelengths 175 nm and 175.5 nm
- Reciprocal linear dispersion at photocathode = 4.437nm/mm



#### Horizontal lineout averaged vertically







## OTS telescope assembly is the third of three key modules in the detector assembly



OTS telescope assembly is assembled and aligned offline prior to being installed in the final DIM assembly.



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### **OTS telescope assembly**



- Telescope assembly
  - MgF2 blast shield
  - Off-axis Schwarzchild telescope (f/8.3)
  - FOV at TCC: (+/-) 3 mm, (+/-) 8 mm 50% vignetting
  - Magnification: 2.7
  - Illumination laser diodes (660nm)
  - Band-pass filters
  - Off-axis parabola
  - ATLAS alignment SMRs



### **OTS telescope assembly debris wind analysis** shows a factor of 6 safety margin for NIF

- Simulation covers a front window and telescope face plate. Pressure time history is analyzed.
- Analysis shows peak stress in the Aluminum housing is 35MPa, yielding a 6X safety factor
- The blast window stresses are approximately 21MPa
- Evaluation of the MgF2 material is in process, preliminary data show 8mm thickness will provide adequate safety margin.









# OTS diagnostic external alignment tool (ATLAS) will position OTS in the NIF chamber



- ATLAS external alignment interfaces
  - ATLAS alignment can view equator and polar locations
  - ATLAS SMRs are placed for two different location.
  - ATLAS placement of DIM is (< 200 um). System is being commissioned and will have better numbers is a few months.

ATLAS view of DIM based diagnostics



### OTS diagnostic telescope incorporates an internal alignment camera as one of two alignment aids for OTS



OTS telescope field of view at the pin hole based on a magnification of x2.7. The FOV at TCC is +/- 3 mm at TCC and +/- 8 mm at TCC with 50% vignetting.





#### Image plane at spectrometer pin hole that is viewed by internal alignment sensor for final target alignment.



Telescope FOV at the IP2/pin hole. Pin hole is 0.135 mm, 50um at TCC



Hohlraum target at TCC imaged at IP2 pin hole after x2.7 magnification, equatorial view



# Hohlraum at TCC viewed by the OTS alignment camera, equatorial view



Alignment CCD sensor active area

Target overlay on CCD sensor, equatorial view

Alignment sensor-Sony (ICX285AL) 6.45um pixel pitch, 1:1 image relay, corresponding to ~21 pixels across the pin hole. This provides 2.5 mm vertical coverage at TCC.



# Hohlraum at TCC viewed by the OTS alignment camera, polar view



Target overlay at pin hole after x2.7 magnification, polar view



Hohlraum target at TCC imaged at IP2 pin hole after x2.7 magnification, polar view



### **Alignment sensor specification for the OTS** alignment camera, including illumination response

#### SONY

Diagonal 11 mm (Type 2/3) Progressive Sca Sensor with Square Pixel for B/W Cameras

Quantum Efficiency

50

30 20

320

#### Description

The ICX285AL is a diagonal 11 mm (Type 2/3) interline CCD solid-state image sensor with a square pixel array. High sensitivity and low smear are achieved through the adoption of EXview HAD CCD technology. Progressive scan allows all pixel's signals to be output independently within approximately 1/15 second. Also, the adoption of high frame rate readout mode supports 60 frames per second. This chip features an electronic shutter with variable charge-storage time which makes it possible to realize full-frame still images without a mechanical shutter. This chip is suitable for image input applications such as still cameras which require high resolution, etc.



| CX285AL   |   | Sensor                                 |  |  |
|---|---|--|--|--|
| In CCD Image  | Sensor  | Sony ICX285                            |  |  |
| pin DIP (Ceramic)   | Туре  | Inter Line Transfer (ILT)              |  |  |
|   | Resolution  | 1392(H) x 1040(V) Color & Mono         |  |  |
| There are a second secon | Pixel Pitch   | 6.45 μm x 6.45 μm                      |  |  |
| Allhi.  | Active Area   | 8.98. mm x 6.70. mm - 11.2 mm diagonal |  |  |
|   | Max Datarate  | 28 MHz                                 |  |  |
| Sony ICX285 CCD Se  | ensor   |  |  |  |
|   |   |  |  |  |
|   |   |  |  |  |
|   |   |  |  |  |
|   |   |  |  |  |
| <b>/</b>  |   | 660 nm Illumination                    |  |  |
|   |   |  |  |  |
|   |   | source wavelength                      |  |  |
|   |   | <b>***</b>                             |  |  |
| 250<br>250<br>250<br>250<br>250<br>250<br>250<br>250<br>250<br>250  | 7240<br>7780<br>8200<br>8200<br>840<br>860<br>9200<br>9200<br>940 | 960<br>1020<br>1020                    |  |  |
| Wavelength (nn  | n)  |  |  |  |

Alignment sensor-Sony (ICX285AL) 6.45um pixel pitch, and provide 2.5 mm vertical coverage at TCC.



# Remaining physics and engineering issues for OTS

- Blanking studies for debris window
- Improved mechanical stress models for window material
- Coating damage studies
- Completing the gated circuit prototype
- Background estimate model improvement



# OTS high level schedule for remaining phase 1 and the addition of phase 2





### **Backup Slides**





# OTS unfolded optical layout describing the optical components in the measurement system



- Labeled f/#s are from using D1=154.3mm (beam diameter at primary)
- The IAW magnification is optimized for the resolution element of recording systems.

OTS unfolded layout describes the optical components in the measurement system.



### OTS spectrometer group assembly for the IAW and EPW







# OTS spectrometer group optical path diagram, (top view)







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### OTS diagnostic photodiode (SiC), light collection transmission monitor



| ELECTRO-OPTICAL CHARACTERISTICS AT 25°C |   |                               |     |     |     |                 |  |  |
|---|---|-------------------------------|-----|-----|-----|-----------------|--|--|
|   | PARAMETERS                                | TEST CONDITIONS               | MIN | TYP | MAX | UNITS           |  |  |
|   | Active Area                               | 1mm x 1mm                     |     | 1   |     | mm <sup>2</sup> |  |  |
|   | Responsivity, R                           | (see graphs on next page)     |     |     |     | A/W             |  |  |
|   | Reverse Breakdown Voltage, V <sub>R</sub> | I <sub>R</sub> = 1μA          | 55  |     |     | Volts           |  |  |
|   | Capacitance, C                            | $V_{R} = 0V$                  |     |     | 40  | pF              |  |  |
|   | Rise Time                                 | $RL = 50\Omega$ , $V_R = 52V$ |     |     | 700 | psec            |  |  |
|   | Dark Current                              | V <sub>R</sub> = 52V          | 0   |     | 1   | nA              |  |  |

- SiC photodiode is used as a transmission monitor for the diagnostic.
- Diode locations
  - Pin hole
  - IAW-G1, "0 order" reflection





### **Typical Holhraum target**

THD\_Au\_575.1013\_337\_HDC5.9\_C\_14-104187



Target Dimensions Length: 10.3 mm Width: TBD





## OTS controls point diagram that describes the DIM based automation



Optical Thomson Diagnostic is a DIM based diagnostic platform designed to operate in the polar and equatorial locations. All the controls will operate at both locations.



## OTS wavelength diagram describing the optical band-pass for telescope and spectrometers



OTS wavelength diagram describes the band-pass of the optical collection systems.



